## Search Notes



## Application/Control No.

Applicant(s)/Patent under Reexamination 10/752,642 NAKAMURA ET AL.

Examiner CHRIS C. CHU Art Unit

2815

SEARCHED					
Class	Subclass	Date	Examiner		
257	E21.584, E21.582 & E21.174	1/26/2009	c.c.		
257	758 & 751	1/26/2009	C.C.		
257	762 & 763	1/26/2009	C.C.		

Class	Subclass	Date	Examiner
			+

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPC, JPO; DERWENT; and IBM_TDB;	1/26/2009	C.C.		